

IN THE U.S. PATENT AND TRADEMARK OFFICE  
May 14, 2008

Applicants : Yoshio KAJIYA et al  
 Title : METHOD OF PRODUCING CATHODE MATERIAL FOR  
 LITHIUM SECONDARY CELL

Serial No. : 10/521 370 Group: 1795

Confirmation No.: 2268

Filed : January 12, 2005 Examiner: Echelmeyer

International Application No.: PCT/JP2003/002027

International Filing Date : February 25, 2003

Atty. Docket No.: 4402.P0666US

Mail Stop AF  
 Commissioner for Patents  
 P.O. Box 1450  
 Alexandria, VA 22313-1450

**PETITION FOR TIME EXTENSION, AND CERTIFICATE OF MAILING**

Sir:

A Notice of Appeal is enclosed.

Pursuant to 37 CFR 1.136(a), please extend the shortened period for response by three months. The extension fee is:

\$1,050.00 (37 CFR 1.17)

A check for \$1,560.00 is enclosed to cover fees.

If this Petition is not timely received, please extend the shortened period an additional month. Please credit any over-payment, or charge any additional fee required by this Petition, to Deposit Account No. 06-1382. A duplicate of this Petition is enclosed.

Respectfully submitted,

  
 Terryence F. Chapman

IN DUPLICATE  
 TFC/smd

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\*limited recognition number

Encl: Check

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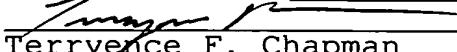
Notice of Appeal dated May 14, 2008

02 FC:1253

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**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on May 14, 2008.

  
 Terryence F. Chapman